

Form PTO-1449

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HARRIS ET AL.

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Art Unit: n/a

## U.S. PATENT DOCUMENT

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
MB	5 8 5 0 1 1 8	12/98	TODA			
	5 8 3 1 4 9 2	11/98	SOLIE			
	4 6 0 0 9 0 5	07/86	FREDRICKSEN			
	5 8 1 8 3 1 0	10/98	SOLIE			

## FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	
1 9 7 0 6 4 86	08/98	FED. REP. GERMANY			

Streibl, M. et al. "SAW Tomography-Spatially Resolved Charge Detection by SAW in Semiconductor Structures

for Imaging Applications", 1999 IEEE Ultrasonics Symposium Proceedings. International Symposium (Cat. No. 99CH 37027),

1999 IEEE Ultrasonics Symposium, Proceedings. International Symposium. Caesars Tahoe, NV, U.S.A. 17-20 Oct. 1999, Pages

11-14, Vol. 1, XP002156577, 1999, Piscataway, NJ, U.S.A., IEEE, U.S.A., ISBN: 0-7803-5722-1

EXAMINER

O. BUDD  
PRIMARY EXAMINER

DATE CONSIDERED

4-24-03

EXAMINER: Initial citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

(Form PTO-1449 [6-4])